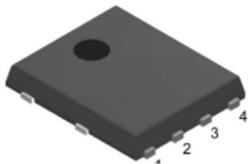


N-Channel Enhancement Mode Logic Level 40V, 0.8mΩ max, 360A  
STripFET F8 Power MOSFET in a PowerFLAT 5x6 package

## Pre-Release Data

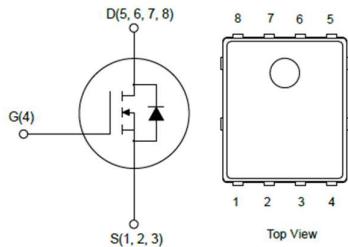
### Features



PowerFLAT 5x6

Order Code	V <sub>DS</sub>	R <sub>DS(on)</sub> max	I <sub>D</sub>
STL320N4LF8	40 V	0.8 mΩ at 10V	360 A

- MSL1 grade
- 175°C operative temperature
- 100% avalanche tested



### Applications

- Switching applications

### Description

This N-channel Power MOSFET utilizes STripFET F8 with an enhanced trench gate structure that results in very low on-state resistance, while also reducing internal capacitances and gate charge for faster and more efficient switching.



Product summary	
Order code	STL320N4LF8
Marking (1)	320N4LF8
Package	PowerFLAT 5x6
Packing	Tape and reel

## 1 Electrical ratings

( $T_C = 25^\circ\text{C}$  unless otherwise specified)

**Table 1.** Absolute maximum ratings

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain-source voltage	40	V
$V_{GS}$	Gate-source voltage	$\pm 20$	V
$I_D^{(2)}$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	360	A
	Drain current (continuous) at $T_C = 100^\circ\text{C}$	254	
$I_{DM}^{(3,4)}$	Drain current (pulsed), $t_P = 10\mu\text{s}$	1440	A
$P_{TOT}$	Total power dissipation at $T_C = 25^\circ\text{C}$	188	W
$I_{AS}$	Single pulse avalanche current (pulse width limited by $T_J$ max)	60	A
$E_{AS}$	Single pulse avalanche energy (starting $T_J = 25^\circ\text{C}$ , $I_D = 60\text{A}$ , $R_{Gmin} = 25\Omega$ )	590	mJ
$T_J$	Operating junction temperature range	-55 to 175	$^\circ\text{C}$
$T_{stg}$	Storage temperature range		

**Table 2.** Thermal data <sup>(3)</sup>

Symbol	Parameter	Value	Unit
$R_{thJA}^{(5)}$	Thermal resistance junction-ambient max. (on 2s2p FR-4 board vertical in still air)	20	$^\circ\text{C/W}$
$R_{thJC}$	Thermal resistance junction-case max.	0.8	$^\circ\text{C/W}$

## 2 Electrical characteristics

( $T_J = 25^\circ\text{C}$  unless otherwise specified)

**Table 3.** On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$V_{\text{GS}} = 0\text{V}, I_D = 1\text{mA}$	40			V
$I_{\text{DSS}}$	Zero gate voltage drain current	$V_{\text{DS}} = 40\text{V}, V_{\text{GS}} = 0\text{V}$			1	$\mu\text{A}$
		$V_{\text{DS}} = 40\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}^{(3)}$			100	
$I_{\text{GSS}}$	Gate-body leakage current	$V_{\text{GS}} = 20\text{V}, V_{\text{DS}} = 0\text{V}$			100	nA
$V_{\text{GS}(\text{th})}$	Gate threshold voltage	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	1.2		2.0	V
$R_{\text{DS}(\text{on})}$	Static drain-source on-resistance	$V_{\text{GS}} = 10\text{V}, I_D = 60\text{A}$		0.55	0.8	$\text{m}\Omega$
		$V_{\text{GS}} = 4.5\text{V}, I_D = 60\text{A}$		0.85	1.15	
$R_G^{(3)}$	Gate resistance			1.2		$\Omega$

**Table 4.** Dynamic <sup>(3)</sup>

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{\text{iss}}$	Input capacitance	$V_{\text{DS}} = 25\text{V}, f = 1\text{MHz}, V_{\text{GS}} = 0\text{V}$		7657		pF
$C_{\text{oss}}$	Output capacitance			1968		pF
$C_{\text{rss}}$	Reverse transfer capacitance			50		pF
$Q_g$	Total gate charge	$V_{\text{DD}} = 20\text{V}, I_D = 60\text{A}, V_{\text{GS}} = 0 \text{ to } 4.5\text{V}$		41		nC
		$V_{\text{DD}} = 20\text{V}, I_D = 60\text{A}, V_{\text{GS}} = 0 \text{ to } 10\text{V}$		96		
$Q_{\text{gs}}$	Gate-source charge	$V_{\text{DD}} = 20\text{V}, I_D = 60\text{A}, V_{\text{GS}} = 0 \text{ to } 4.5\text{V}$		20		nC
$Q_{\text{gd}}$	Gate-drain charge			6.9		nC
$Q_{\text{g(sync)}}$	Total gate charge, sync. MOSFET	$V_{\text{DS}} = 0.1\text{V}, V_{\text{GS}} = 0 \text{ to } 4.5\text{V}$		43		nC
$Q_{\text{oss}}$	Output charge	$V_{\text{DD}} = 20\text{V}, V_{\text{GS}} = 0\text{V}$		102		nC

**Table 5.** Switching times <sup>(3)</sup>

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 20V, I_D = 60A, R_G = 4.7\Omega, V_{GS} = 10V$		12.3		ns
$t_r$	Rise time			6.3		ns
$t_{d(off)}$	Turn-off delay time			89.2		ns
$t_f$	Fall time			21		ns

**Table 6.** Source-drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}^{(2,3)}$	Forward on current (continuous)	$T_C = 25^\circ C$			135	A
$V_{SD}$	Forward on voltage	$I_{SD} = 60A, V_{GS} = 0V$			1.1	V
$t_{rr}^{(3)}$	Reverse recovery time	$I_D = 60A, dI/dt = 100A/\mu s, V_{DD} = 32V$		60.1		ns
$Q_{rr}^{(3)}$	Reverse recovery charge			74.4		nC
$I_{RRM}^{(3)}$	Reverse recovery current			2.5		A

<sup>(1)</sup> For engineering samples marking, see *PowerFLAT 5x6 package marking information*.

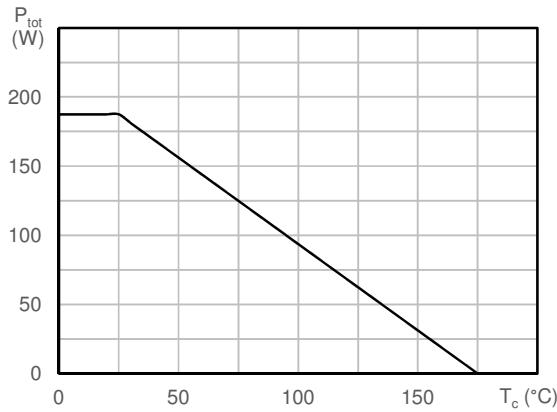
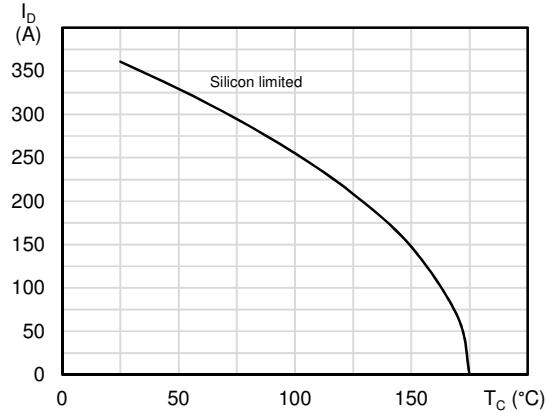
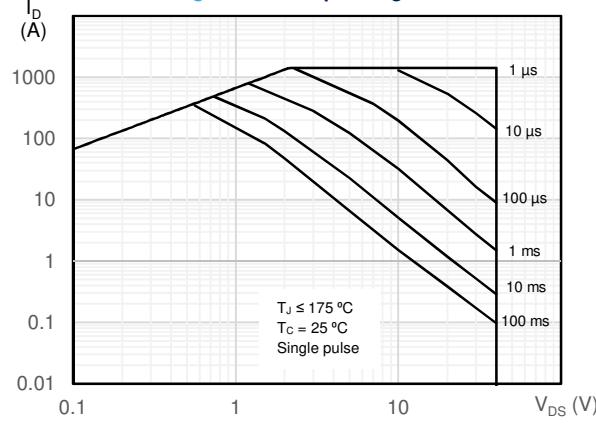
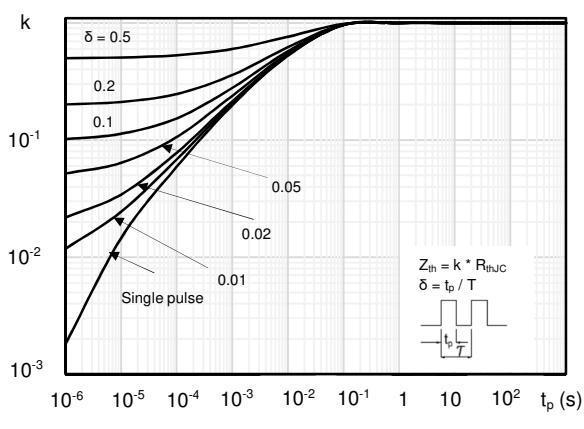
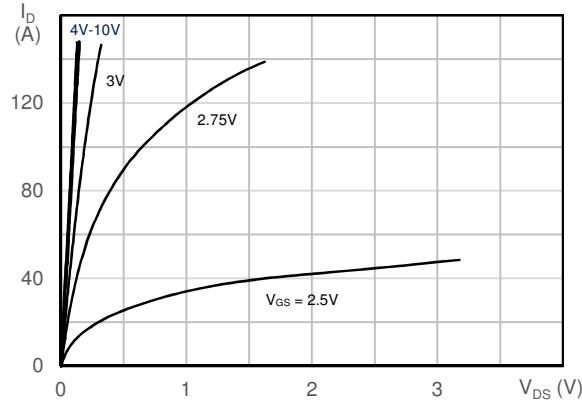
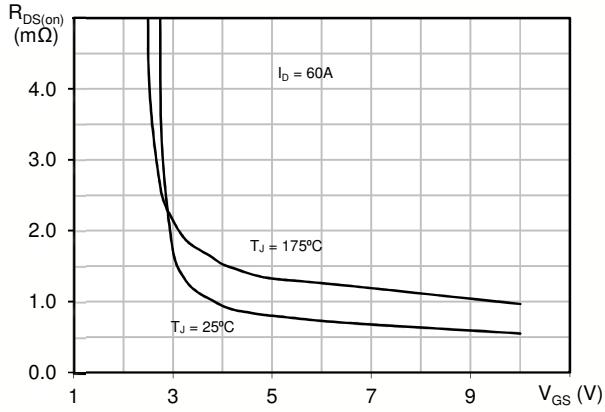
<sup>(2)</sup> The value is relevant to  $R_{thJC}$ . Current limitations will come from the operative conditions, such as temperature and thermal resistance of the PCB.

<sup>(3)</sup> Specified by design and evaluated by characterization, not tested in production.

<sup>(4)</sup> Pulse width is limited by safe operating area.

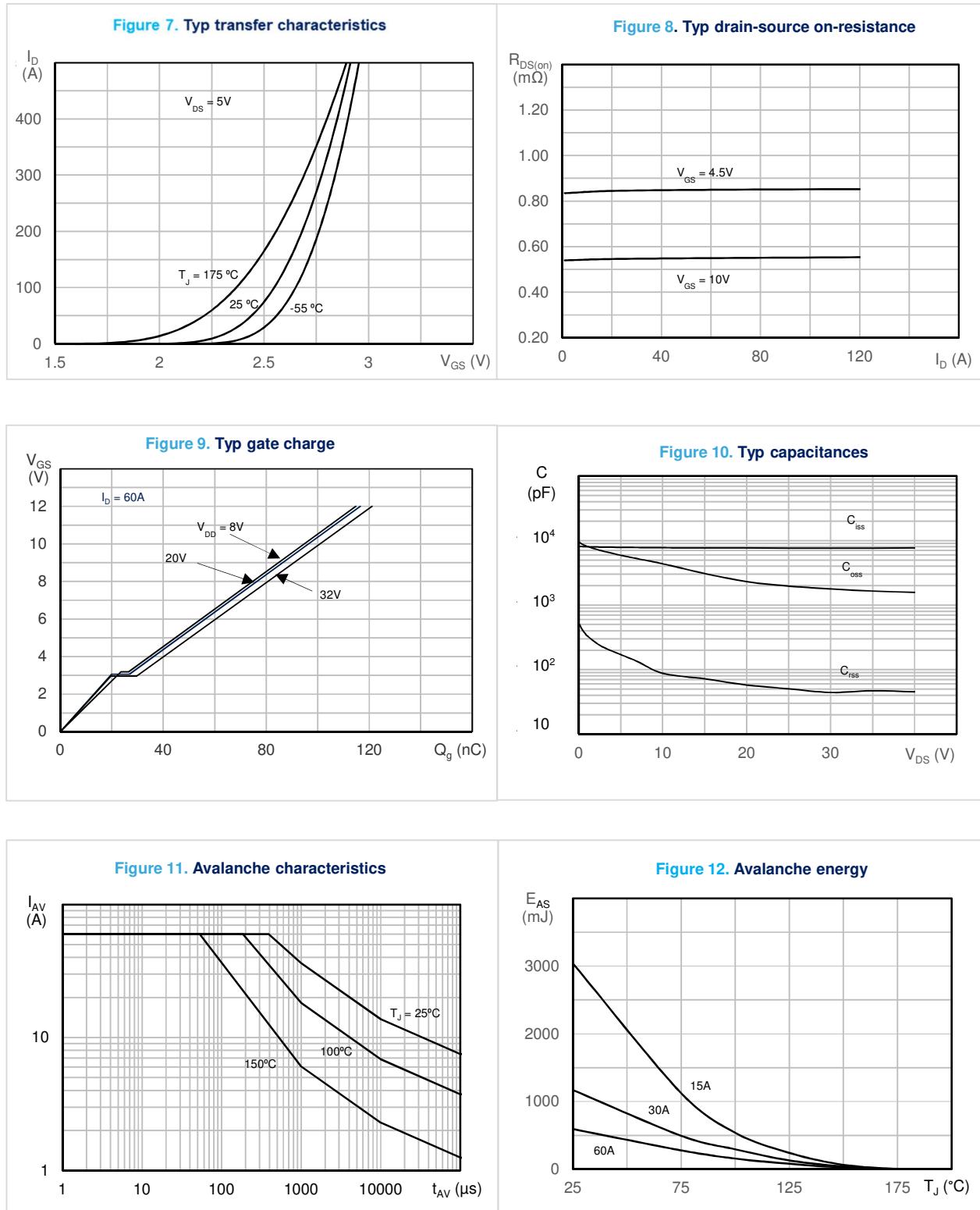
<sup>(5)</sup> Defined according to JEDEC standards (JESD51-5, -7).

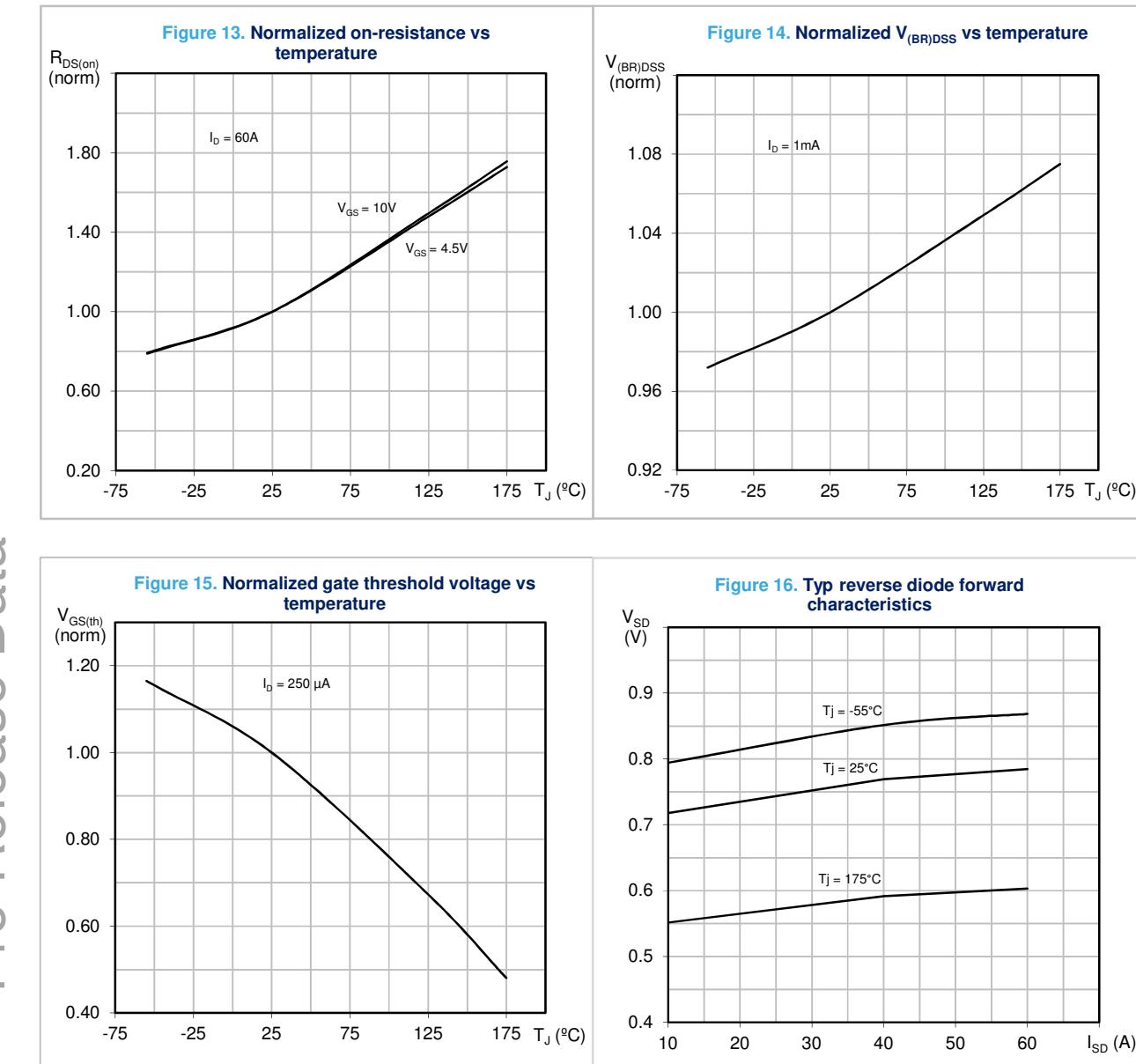
## 2.1 Electrical characteristics (curves)

**Figure 1. Power dissipation**

**Figure 2. Drain current**

**Figure 3. Safe operating area**

**Figure 4. Normalized transient thermal impedance**

**Figure 5. Typ output characteristics**

**Figure 6. Typ on-resistance vs gate-source voltage**


## Electrical characteristics (curves)

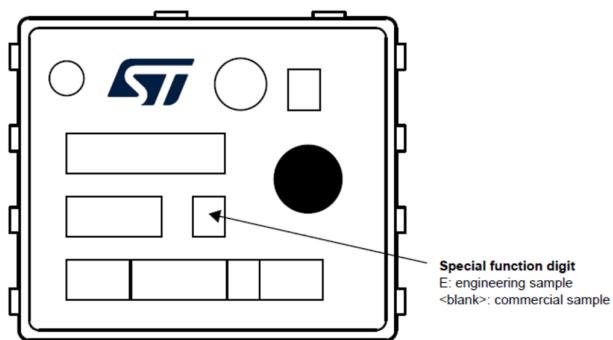
## Pre-Release Data





### 3 PowerFLAT 5x6 package marking information

Figure 17. PowerFLAT 5x6 package marking information



Notes:

*Engineering Samples are clearly identified with a dedicated special symbol in the marking of each unit. These samples are intended to be used for electrical compatibility evaluation only. Usage for any other purpose may be agreed only upon written authorization by ST. ST is not liable for any customer usage in production and/or in reliability qualification trials.*

*Commercial Samples are fully qualified parts from ST standard production with no usage restrictions.*

## Pre-Release Data

## Revision History

Table 7. Document revision history

Date	Revision	Changes
3-Mar-2022	0.1	Pre-release data